

EECS 312 Discussion 4

10/01/10

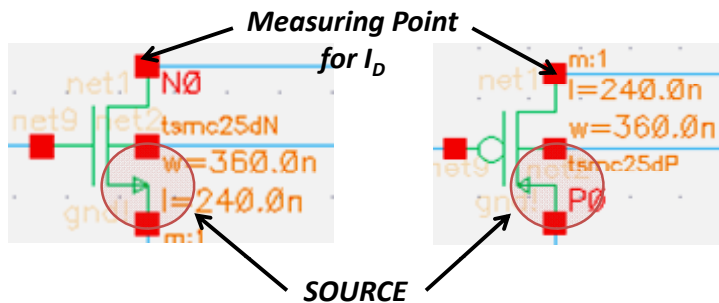
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Overview

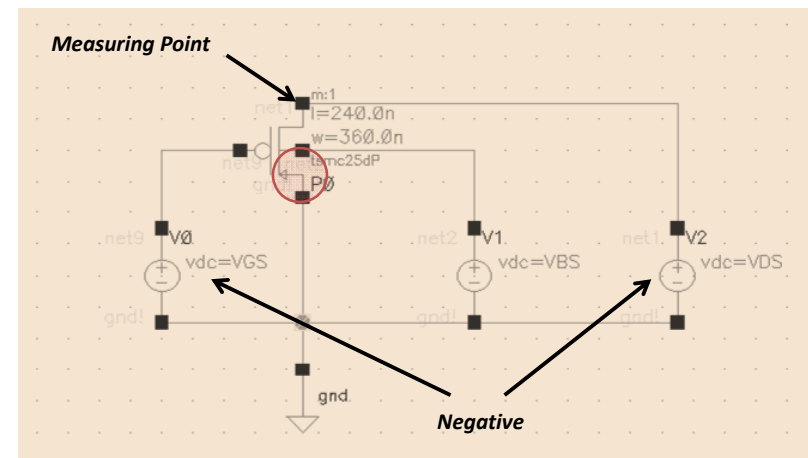
- Reminder
 - Lab Project 2: Due Monday (Oct 4)
 - Office hour: Monday 3:30-5:00pm (CAEN Lab)
 - In-out box: Outside EECS 2417-G
- Lab Project 2 Help
- CMOS Fabrication

MOSFET Symbol

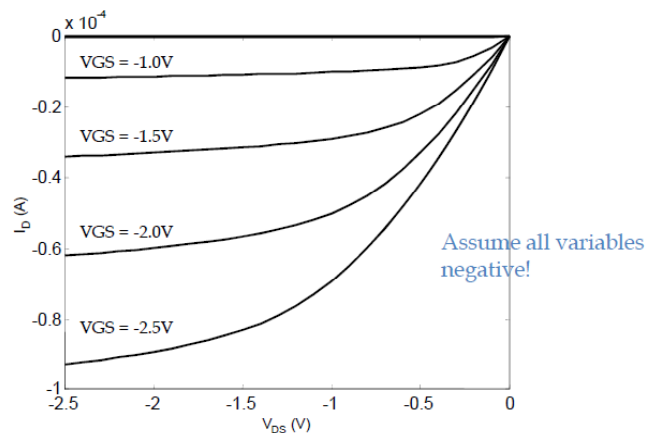
- For both PMOSFETs and NMOSFETs, the arrow is on the source side of the gate, and points in the direction of current
- In the NMOSFET symbol, the arrow points away from the gate
- In the PMOSFET symbol, the arrow points toward the gate



Lab 2 Part2 – PMOS characterization



Lab 2 Part2 – PMOS characterization



(From lecture slide)

Lab 2 Part 3 – Body Bias

$$I_D = k' \frac{W}{L} \left(V_{GT} V_{min} - \frac{V_{min}^2}{2} \right) (1 + \lambda V_{DS}) \text{ for } V_{GT} \geq 0$$

$$\text{with } V_{min} = \min(V_{GT}, V_{DS}, V_{DSAT}),$$

$$V_{GT} = V_{GS} - V_T,$$

$$\text{and } V_T = V_{T0} + \gamma (\sqrt{|-2\phi_F + V_{SB}|} - \sqrt{|-2\phi_F|})$$

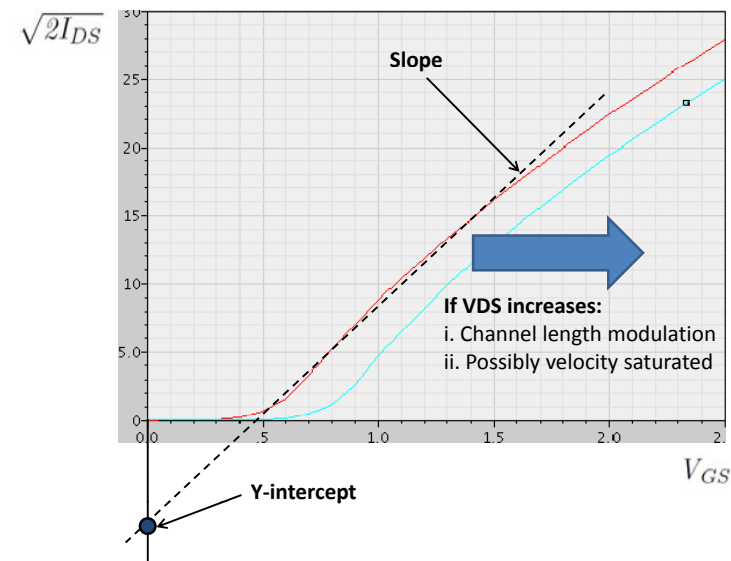
- We already have found k' , V_{T0} , and λ
- We can obtain I_D from simulation
- Two unknowns – γ , ϕ_F
 - $2\phi_F$ is negative in NMOS and positive in PMOS
 - γ is positive in NMOS and negative in PMOS
 - If $V_{SB}=0$, simply $V_T=V_{T0}$

Lab 2 Part 5 – Alternate Method

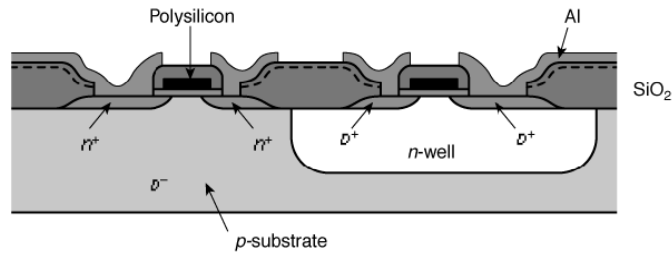
- Determine V_T and k based on

$$I_D = \frac{k'}{2} \frac{W}{L} (V_{GS} - V_T)^2 \quad , \text{so } V_{GS} \propto \sqrt{2I_{DS}}$$

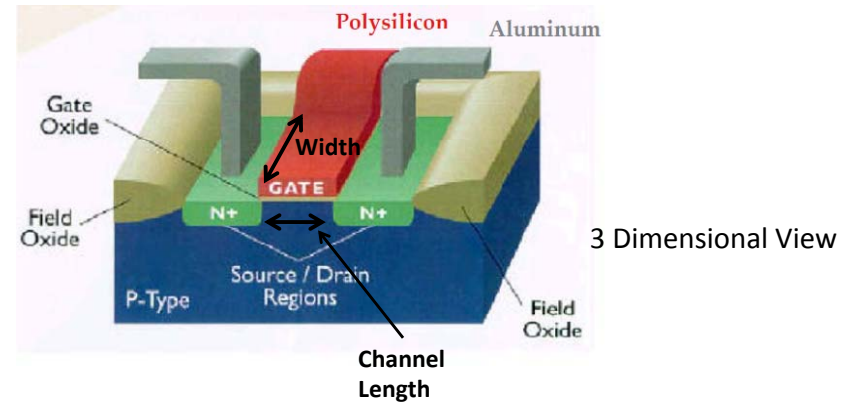
- Drain and gate are shorted forcing $V_{DS} = V_{GS}$ and therefore $V_{DS} > V_{GS} - V_{T0}$ for all V_{GS} , keeping it in saturation but ideally not velocity saturation
- Take five points along the most linear portion of the curve and use linear regression software to fit a line to them with minimal error.



CMOS Process

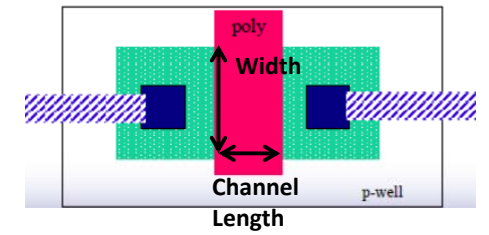


Cross-Sectional View

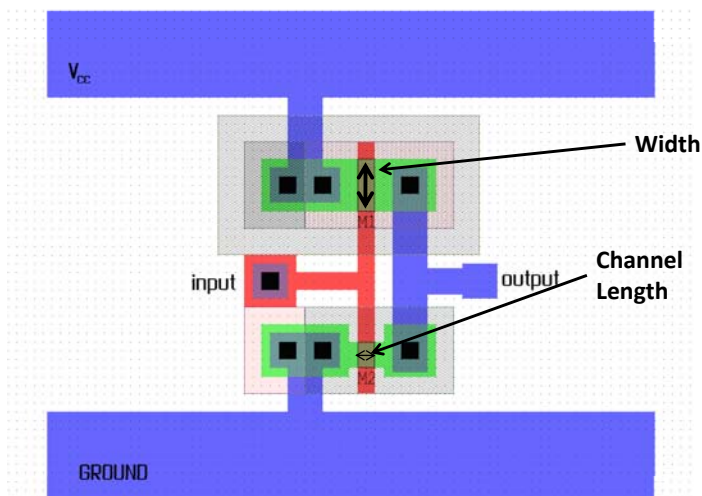


3 Dimensional View

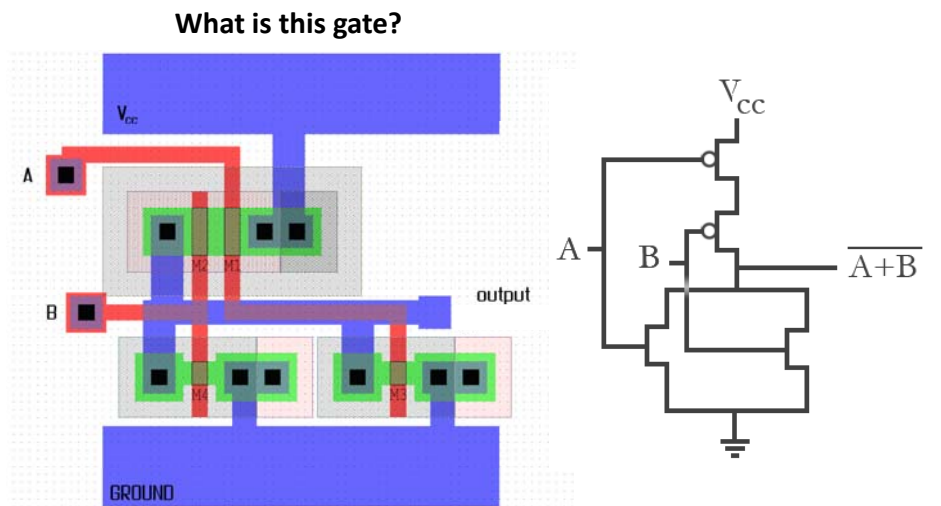
Layout View



Inverter Layout

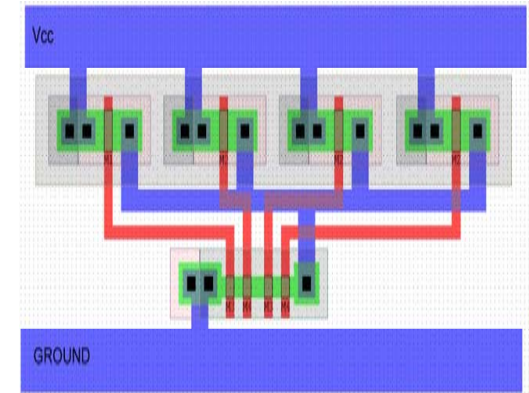
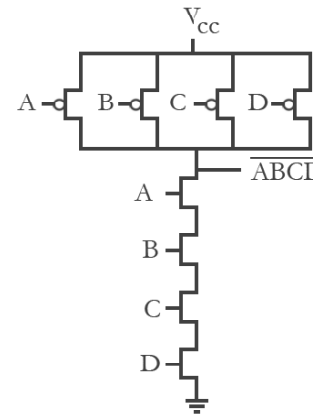
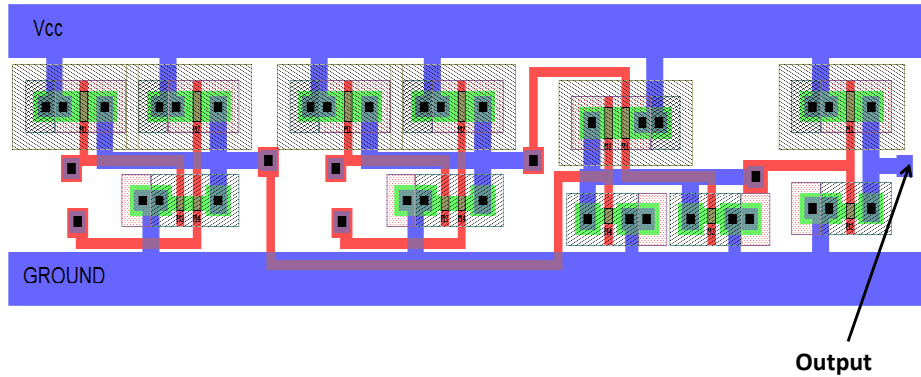


Exercise 1

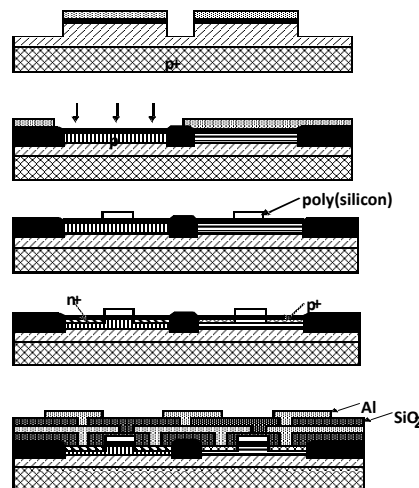
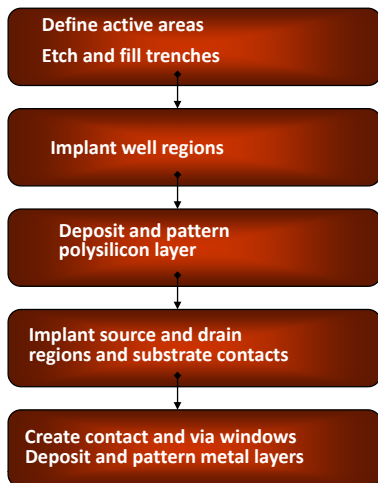


Exercise 2

1. Draw gate-level schematic for the layout
2. Decide the functionality



CMOS Process at a Glance



Intel 45nm Interconnects (Cross Section View)

Loose pitch + thick metal on upper layers

- High speed global wires
- Low resistance power grid

Tight pitch on lower layers

- Maximum density for local interconnects

